

**Notice of References Cited**Application/Control No.  
09/558,645Applicant(s)/Patent Under  
Reexamination  
KAPLAN ET AL.Examiner  
Lynne R. EdmondsonArt Unit  
1725

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**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
	A	US-5458993 ✓	10-1995	Terao et al.	429	94
	B	US-3945847 ✓	03-1976	Kordesch et al.	136	100R
	C	US-5800939 ✓	09-1998	Mishina et al.	429	57
	D	US-6183668 B1 ✓	12-1998	Debe et al.	252	510
	E	US-4582553 ✓	04-1986	Buchta	156	242
	F	US-6280879 B1 ✓	12-1998	Anderson et al.	429	233
	G	US-5401590 ✓	03-1995	Chalilpoyil et al.	429	59
	H	US-5308711 ✓	05-1994	Passaniti et al.	429	29
	I	US-5707763 ✓	01-1998	Shimizu et al.	429	217
	J	US-4935317 ✓	06-1990	Fauteux et al.	429	192
	K	US-6207322 B1 ✓	03-2001	Kelsey et al.	429	206
	L	US-				
	M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY				
	N	JP 50-67431 A ✓	06-1975	Japan	Yuasa	429	224
	O	DE 3242139 A1 ✓	05-1984	Germany	Kohlhase et al.	429	224
	P						
	Q						
	R						
	S						
	T						

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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